

<b>Notice of References Cited</b>	Application/Control No. 10/064,471		Applicant(s)/Patent Under Reexamination RAHN, JEFFREY	
	Examiner Allen C. Ho		Art Unit 2882	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,844,682	12-1998	Kiyomoto et al.	356/237.1
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Nicholas Tsoulfanidis. Measurement and Detection of Radiation, second edition (Washington, DC: Taylor & Francis, 1995), p. 235-263.
	V	Amnon Yariv. Optical Electronics, third edition (New York, NY: Holt, Rinehart, and Winston, Inc., 1985), p. 367-376 and Fig. 11-15.
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.